



12500 TI Boulevard, MS 8640, Dallas, Texas 75243

**PCN# 20120517001**  
**Qualification of JCAP as an Additional Assembly, Bump, and Test site**  
**for the TPS62650YFFR/T and TPS62651YFFR/T Devices**  
**Change Notification / Sample Request**

**Date:** 6/1/2012  
**To:** Newark PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager ([PCN\\_ww\\_admin\\_team@list.ti.com](mailto:PCN_ww_admin_team@list.ti.com)).

Sincerely,

PCN Team  
SC Business Services  
Phone: +1(214) 480-6037  
Fax: +1(214) 480-6659

**20120517001**  
**Attachment: 1**

**Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

<b>DEVICE</b>	<b>CUSTOMER PART NUMBER</b>
TPS62651YFFT	null

Technical details of this Product Change follow on the next page(s).

<b>PCN Number:</b>	20120517001		<b>PCN Date:</b>	06/01/2012									
<b>Title:</b>	Qualification of JCAP as an Additional Assembly, Bump, and Test site for the TPS62650YFFR/T and TPS62651YFFR/T Devices												
<b>Customer Contact:</b>	<a href="#">PCN Manager</a>	<b>Phone:</b>	+1(214)480-6037	<b>Dept:</b> Quality Services									
<b>Proposed 1<sup>st</sup> Ship Date:</b>	09/01/2012	<b>Estimated Sample Availability:</b>	Date Provided at Sample request										
<b>Change Type:</b>													
<input checked="" type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Assembly Materials								
<input type="checkbox"/>	Design	<input type="checkbox"/>	Electrical Specification	<input type="checkbox"/>	Mechanical Specification								
<input checked="" type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process								
<input checked="" type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material	<input type="checkbox"/>	Wafer Bump Process								
<input type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Wafer Fab Materials	<input type="checkbox"/>	Wafer Fab Process								
<b>PCN Details</b>													
<b>Description of Change:</b>													
Qualification of JCAP as an Additional Assembly, Bump, and Test site for the TPS62650YFFR/T and TPS62651YFFR/T Devices. Current site is in TI-Clark. Assembly differences are shown in the following table:													
	<b>Clark-AT</b>	<b>JCAP-AT</b>											
<b>Bump Site</b>	Clark-BP	JCAP-FAB											
<b>Solder Ball</b>	4207848	MA22008110											
Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.													
<b>Reason for Change:</b>													
Continuity of supply.													
<b>Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):</b>													
None													
<b>Changes to product identification resulting from this PCN:</b>													
<table border="1"> <tr> <td colspan="3">Assembly Site</td> </tr> <tr> <td>Clark-AT</td> <td>Assembly Site Origin (22L)</td> <td>ASO: QAB</td> </tr> <tr> <td>JCAP-AT</td> <td>Assembly Site Origin (22L)</td> <td>ASO: JCP</td> </tr> </table>					Assembly Site			Clark-AT	Assembly Site Origin (22L)	ASO: QAB	JCAP-AT	Assembly Site Origin (22L)	ASO: JCP
Assembly Site													
Clark-AT	Assembly Site Origin (22L)	ASO: QAB											
JCAP-AT	Assembly Site Origin (22L)	ASO: JCP											
<b>Sample product shipping label to show code location only - not actual product label</b>													
<p> <b>TEXAS INSTRUMENTS</b>          MADE IN: Philippines          2DC: 2Q: 676381          MSL 3 /260C/168 HR          SEAL DT 10/11/11          OPT: ITEM: 030DB107CMR-Q&amp; 19          LBL: 1A (L)T0:1168       </p> <p>         (1P) PTWL6030DB107CMR          (Q) 1908 (D) 1136          (31T) LOT: 1606673PHI          (4W) SWR(1T) 8550440Z48          (P)          (2P) REV: A (V) 0033317          (20L) CS0: RFB (21L) CC0: USA          (22L) ASO: PHI (23L) ACO: PHL       </p>													
Assembly Site Code: Clark-AT=I, JCAP-AT=P													

Product Affected:			
TPS62650YFFR	TPS62650YFFT	TPS62651YFFR	TPS62651YFFT

### Qualification Plan

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.			
Qual Vehicle: TPS62651YFFR (MSL1-260C)			
<b>Qualification Schedule:</b>	<b>Start:</b>	June 2012	<b>End:</b> August 2012
Package Construction Details			
<b>Assembly &amp; Bump Site:</b>	JCAP	<b>Bump Composition:</b>	SnAgCu
<b># Pins-Designator, Family:</b>	6-YFF, WCSP/DSBGA	<b>Bump Diameter:</b>	0.25mm
<b>Qualification:</b> <input checked="" type="checkbox"/> Plan <input type="checkbox"/> Test Results			
Reliability Test	Conditions		Sample Size/Fail
			Lot#1
Electrical Characterization	--		5/0
Manufacturability (Assembly)	(per mfg. Site specification)		1/0
BUMP MQ	(per mfg Site specification)		1/0
Notes: ** Tests require preconditioning sequence: MSL1-260C			

### Reference Qualification:

Qualification Plan				
Qual Vehicle: TPS2025YFF (MSL1-260C)				
<b>Qualification Schedule:</b>	<b>Start:</b>	May 2012	<b>End:</b> July 2012	
Package Construction Details				
<b>Assembly &amp; Bump Site:</b>	JCAP	<b>Bump Composition:</b>	SnAgCu	
<b># Pins-Designator, Family:</b>	6-YFF, WCSP/DSBGA	<b>Bump Diameter:</b>	0.25mm	
<b>Qualification:</b> <input checked="" type="checkbox"/> Plan <input type="checkbox"/> Test Results				
Reliability Test	Conditions		Sample Size/Fail	
			Lot#1	Lot#2
Electrical Characterization	--		10/0	--
**High Temp. Storage Bake	170C (420hrs)		45/0	--
**Biased HAST	130C/85%RH (96 Hrs)		77/0	77/0
**Unbiased HAST	130C/85%RH (96 Hrs)		77/0	--
**Temperature Cycle	-55C/+125C (1000 Cyc)		77/0	--
Physical Dimensions	(per mechanical drawing)		5/0	--
Manufacturability (Assembly)	(per mfg site specifications)		1/0	--
Backgrinding Characterization	(per mfg site specifications)		1/0	--
BLR TC	-40/125C, 200, 500, 750, 1000 cycles		32/0	--
** - Test requires Moisture Preconditioning (MSL1-260C)				

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	<a href="mailto:PCNAmericasContact@list.ti.com">PCNAmericasContact@list.ti.com</a>
Europe	<a href="mailto:PCNEuropeContact@list.ti.com">PCNEuropeContact@list.ti.com</a>
Asia Pacific	<a href="mailto:PCNAsiaContact@list.ti.com">PCNAsiaContact@list.ti.com</a>
Japan	<a href="mailto:PCNJapanContact@list.ti.com">PCNJapanContact@list.ti.com</a>